

OPTICAL PHASE MEASUREMENT OF TARGET

Background of the Invention

Surface Plasmon Resonance (SPR) relates to optical excitation of a surface plasmon wave along an interface between a conductive film and an adjacent dielectric. At resonance, energy from an incident optical signal is coupled into the surface plasmon wave, resulting in a decrease in the intensity of the optical signal that is reflected from the conductive film at the optical wavelength at which the resonance occurs. A phase transition in the reflected optical signal also occurs at the resonant optical wavelength. The phase of the reflected optical signal at the resonant optical wavelength is sensitive to changes in the refractive index of the dielectric that is adjacent to the conductive film, due to an evanescent tail associated with the surface plasmon wave that extends into the dielectric. This phase sensitivity to refractive index enables the dielectric to be used as a sensing medium. For example, where the dielectric includes a biochemical sample, changes in the refractive index can be used to indicate biochemical conditions or processes in the biochemical sample.

Due to the sensitivity of phase transitions in the reflected optical signal to changes in refractive index of the dielectric or sensing medium, phase measurements based on SPR have been exploited as an analytic tool for biochemical sensing. For example, *Immunosensor based on optical heterodyne phase detection*, Sensors and Actuators B, vol. 76, Xinglong Yu, et al., (2003), p. 199-202, reports interferometry, optical heterodyning and other techniques to detect phase changes corresponding to smaller than micro-unit changes in refractive index that are linked to association/dissociation of antibodies and a protein in a biochemical sample.

There is a continuing need for phase detection schemes to further increase the sensitivity with which changes in refractive indices can be detected. In addition, there is a

need for phase detection schemes based on SPR that are scalable for compatibility with analytical systems that include arrays of samples for biochemical sensing.

Summary of the Invention

5 According to the embodiments of the present invention, optical phase detection includes generating a first lightwave having a first polarization and a second lightwave having a polarization that is offset from the first polarization, and imposing a relative delay between the first and second lightwaves. The imposed delay causes a frequency offset as the wavelength of the lightwaves is tuned over a designated wavelength range.

10 The lightwaves are directed to a target that provides a third lightwave and a fourth lightwave in response to the first and second lightwaves. A polarization component of the third lightwave and a polarization component of the fourth lightwave are detected to provide a detected signal at the frequency offset. The optical phase detection then includes extracting a phase difference, induced by the target, between the polarization components
15 of the third and the fourth lightwaves. According to alternative embodiments of the present invention, scaling of the optical phase detection enables simultaneous or sequential detection of SPR-induced phase shifts from an array of targets.

Brief Description of the Drawings

Figure 1 shows a conventional configuration for a SPR transducer.

Figure 2 shows an example phase versus wavelength for the configuration of Figure 1.

5 Figure 3 shows an optical phase detector according to embodiments of the present invention.

Figures 4A-4B show exemplary implementations of the optical phase detector of Figure 3.

10 Figures 5A-5B show detailed views of the polarized optical signals included in the embodiments of the present invention.

Figure 6 shows exemplary phase contours versus optical wavelength according to embodiments of the present invention.

Figure 7 shows phase transitions versus optical wavelength for different polarization alignments according to embodiments of the present invention.

15 Figures 8A-8B show scaled optical phase detectors according to embodiments of the present invention.

Figure 9 shows a flow diagram of a phase detection method according to alternative embodiments of the present invention.

Detailed Description of the Embodiments

Figure 1 shows a conventional SPR transducer 10, known as the Kretschmann configuration. The SPR transducer 10 includes a conductive film 1 that is adjacent to a dielectric 2. However, in some applications of the SPR transducer 10 the dielectric 2 is a sensing medium, and a linker layer (not shown) is interposed between the conductive film 1 and the dielectric 2 to provide a site for bio-molecular receptors to attach. For clarity, the conductive film 1 in Figure 1 is shown adjacent to the dielectric 2 without the linker layer. A prism 4 is positioned adjacent to a side of the conductive film 1 that is opposite the dielectric 2. The Kretschmann configuration of the SPR transducer 10 is described in a variety of references, including *Simulation and Analysis of Surface Plasmon Resonance Biosensor Based on Phase Detection*, Sensors and Actuators B vol. 91, Xinglong Yu et al. (2003), p285-290.

In a typical application of the SPR transducer 10, the conductive film 1 is a gold layer having an appropriate thickness d_1 for an incident optical signal I_i at a designated incident angle ϕ_{SP} and wavelength to excite a surface plasmon wave, or surface plasmon, along the conductive film 1. Associated with the surface plasmon is an evanescent tail (not shown) that penetrates into the dielectric 2 adjacent to the conductive film 1. The energy of the incident optical signal I_i that is not coupled into the surface plasmon is reflected at the conductive film 1 and results in a reflected optical signal I_r .

Figure 2 shows an exemplary phase contour of the reflected optical signal I_r in the context of the SPR transducer 10 of Figure 1, resulting from the incident optical signal I_i impinging on a target T on the conductive film 1. The phase is indicated versus wavelength λ in the vicinity of the wavelength λ_R at which the incident optical signal I_i

couples to the surface plasmon. This wavelength λ_R is the optical wavelength of the SPR (surface plasmon resonance), and is hereafter referred to as the resonant wavelength λ_R .

Figure 2 indicates that the phase of the reflected optical signal I_r is highly sensitive to the wavelength λ of the incident optical signal I_i in the vicinity of the resonant wavelength

5 λ_R . The resonant wavelength λ_R in turn, is highly sensitive to changes in refractive index n_s of the dielectric 2 due to the evanescent tail that penetrates the dielectric 2. Detecting phase of the reflected optical signal I_r enables changes in refractive index n_s of the dielectric 2 to be detected.

An optical phase detector 20 according to embodiments of the present invention is shown in Figure 3. The optical phase detector 20 includes a tunable optical source 22 that generates an optical signal I_1 . The optical signal I_1 includes a first lightwave having offset a first polarization and a second lightwave having a second polarization that is offset from the first polarization. In a typical example, the offset polarizations of the first and second lightwaves are the conventional polarizations p, s. For the purpose of illustration, the lightwave having the p polarization is referred to as the lightwave p and the lightwave having the s polarization is referred to as the lightwave s.

The tunable optical source 22 includes a delay element 24 that induces a relative delay τ between the lightwaves p, s of the optical signal I_1 . This induced delay τ results in a frequency offset $\gamma\tau$ between the lightwave p and the lightwave s as the wavelength λ of the tunable optical source 22 is tuned or swept at a rate γ over a wavelength range between λ_1 and λ_2 .

Figure 4A shows an embodiment of the present invention wherein the tunable optical source 22 includes a tunable laser 26, cascaded with a polarization delay unit PDU. The tunable laser 26 can be swept over the wavelength range between λ_1 and λ_2 . The wavelength range between λ_1 and λ_2 is sufficiently wide to accommodate shifts in the resonant wavelength λ_R that result from corresponding shifts in the refractive index n_s of the dielectric 2. In one example, the tunable laser 26 is an AGILENT TECHNOLOGIES, INC. model 81680B that can be tuned with a linear ramp within a wavelength range $\lambda_1 - \lambda_2$ of at least 1492-1640 nanometers. The polarization delay unit PDU includes a polarization maintaining fiber coupler 23 that splits an optical signal provided by the tunable laser 26 into a first branch and a second branch. One of the branches, for example the first branch, includes a length of optical fiber 25 to induce the relative delay τ between the light in the first branch and the second branch. The first branch and the second branch are then coupled to a polarizing beam combiner 28 that transmits to a collimator 30 light from the first branch having one polarization, such as the polarization p, and light from the second branch having an offset polarization, such as the polarization s. The polarizing beam combiner 28 provides the lightwaves p, s of the optical signal I_1 .

The polarization delay unit PDU is alternatively implemented using planar optical circuits, wherein the polarization maintaining fiber coupler 23 and the polarizing beam combiner 28 are implemented in planar optics and the delay element 24 is implemented using a planar optical waveguide. In yet another example, the polarization delay unit PDU is implemented using a polarization beam splitter 21, a free space optical path as the delay element 24, and a polarization beam combiner 28, as shown in Figure 4B.

A collimator 30 or other beam conditioning element is coupled to the tunable optical source 22, directing the optical signal I_1 to a target T on the conductive film 1 as shown in Figure 5A. An optical signal I_2 is reflected at the target T. The optical signal I_2 includes a pair of lightwaves p_r , s_r having offset polarizations that correspond to the offset polarizations of the lightwave p and the lightwave s of the optical signal I_1 . The lightwave p has an electric field component that is perpendicular to the plane of the conductive film 1, whereas the lightwave s has an electrical field that lies in the plane of the conductive film 1. The lightwave p couples to the surface plasmon, whereas the lightwave s does not couple to the surface plasmon. Accordingly, the lightwave p_r of the optical signal I_2 undergoes a phase shift at the resonant wavelength λ_R as indicated in Figure 2, whereas a lightwave s_r of the optical signal I_2 does not undergo such a phase shift.

The optical signal I_2 is received by a polarizer 32 having a polarization axis X that is rotationally offset from the polarization axes of the lightwaves p_r , s_r , by 45 degrees as shown in Figure 5A. However, rotational offsets of the polarization axis X of the polarizer 32 from the polarization axes other than 45 degrees are also suitable.

The lightwaves p_r , s_r of the optical signal I_2 interact as a result of passing through the polarizer 32 to form an interference signal $I(t)$ at a detector 34. The interference signal $I(t)$ is expressed in equation (1).

$$I(t) = E_s(t)^2 + E_p(t)^2 + 2E_sE_p \cos(2\pi\gamma\tau t + \Delta\varphi_{sp}) \quad (1)$$

In equation (1), $E_s(t)$, $E_p(t)$ represent the magnitudes of the electrical fields of the lightwaves p_r , s_r , respectively, of the optical signal I_2 ; γ is the rate at which the tunable

optical source 22 is tuned or swept; τ is the relative delay induced between the lightwaves p, s of the optical signal I_1 provided by the tunable optical source 22; and $\Delta\varphi_{sp}$ is the phase difference between the lightwaves p_r , s_r of the optical signal I_2 . Since the lightwave s of the optical signal I_1 does not couple to the surface plasmon, the lightwave s_r of the optical signal I_2 does not experience a phase shift due to SPR. Thus, the phase difference $\Delta\varphi_{sp}$ is the phase shift of the lightwave p_r , designated as the phase φ_p . Because the lightwaves s, s_r traverse the same optical path as the lightwaves p, p_r , determining the phase φ_p of the lightwave p_r relative to the phase of the lightwave s_r provides immunity to mechanical vibration, temperature variations, and other influences.

The interference signal $I(t)$ is intercepted by the detector 34 as the wavelength λ of the tunable optical source 22 is tuned over a wavelength range $\lambda_1 - \lambda_2$ in the vicinity of the resonant wavelength λ_R . The detector 34 is responsive to the term $2E_sE_p \cos(2\pi\gamma\tau t + \varphi_p)$ in the interference signal $I(t)$, and can be filtered or otherwise tuned for responsiveness within a narrow bandwidth about the frequency $\gamma\tau$, to improve sensitivity with which the term $2E_sE_p \cos(2\pi\gamma\tau t + \varphi_p)$ can be measured or detected. The detector 34 provides a detected signal $I_{DET}(t) = K_1 \cos(2\pi\gamma\tau t + \varphi_p)$, where K_1 is a constant and where $\gamma\tau$ is the frequency difference, or beat frequency, between the lightwaves p, s of the optical signal I_1 provided by the tunable optical source 22. The detected signal $I_{DET}(t)$ is typically an electrical signal.

Typically, the detector 34 is a photodiode, photosensor or other suitable transducer for converting an intercepted optical signal into a corresponding electrical signal.

Alternatively, the detector 34 is an array or a two-dimensional grid of detector elements D_1 - D_N that provide a series of electrical signals corresponding to a series of optical signals that are intercepted by each of the detector elements D_1 - D_N .

Including a reference signal I_{REF} in the optical phase detector 20 enables the phase φ_p in the term $2E_s E_p \cos(2\pi\gamma\tau t + \varphi_p)$ of the interference signal $I(t)$ to be isolated. For example, a reference signal I_{REF} tapped from the optical signal I_1 via an optical coupler 37, reflected off a reference target T_{REF} , and passed through the polarizer 32, as shown in the embodiment of Figure 4A, provides an interference signal $I_R(t)$ at a reference detector 34R that includes a term $E_{SREF} E_{PREF} \cos(2\pi\gamma\tau t)$. The reference detector 34R is responsive to the term $E_{SREF} E_{PREF} \cos(2\pi\gamma\tau t)$ in the interference signal $I_R(t)$ and provides frequency reference $I_{RDET}(t) = K_2 \cos(2\pi\gamma\tau t)$, where K_2 is a constant. The frequency reference $I_{RDET}(t)$ is typically an electrical signal.

The detected signal $I_{DET}(t)$ and the frequency reference $I_{RDET}(t)$ from the detectors 34, 34R are applied to a phase comparator, or other processor 36 to extract the phase φ_p . Phase comparators suitable for extracting phase differences between applied signals are well known in the art, and are described, for example, in *Modern Electronic Circuits Reference Manual*, by Markus, John, McGraw-Hill, Inc., ISBN 0-07-040446-1, p. 699. However, any suitable processor 36 is used to extract or otherwise determine the phase φ_p from the detected signal $I_{DET}(t)$ and frequency reference $I_{RDET}(t)$.

Figure 4A shows the reference optical signal I_{REF} incident on the reference target T_{REF} causing the reference optical signal I_{REF} to traverse an optical path parallel to that traversed by the signals I_1 , I_2 . When the reference target T_{REF} in the optical path of the reference signal I_{REF} does not support excitation of a surface plasmon at the resonant

wavelength λ_R , the reference signal I_{REF} does not undergo a phase shift associated with SPR. The detected phase is then attributable to the refractive index of the dielectric 2 of the target T. When the reference target T_{REF} in the optical path of the reference signal I_{REF} supports excitation of a surface plasmon at the resonant wavelength λ_R , the reference
 5 signal I_{REF} undergoes a phase shift associated with SPR. Here, the detected phase is a differential phase that is attributable to the difference between the refractive index of dielectric 2 of the target T and the refractive index of the dielectric of the reference target T_{REF} .

While exemplary schemes for providing the reference optical signal I_{REF} have been
 10 presented, it is appreciated that any other suitable system, device, element or scheme is alternatively used to provide the reference optical signal I_{REF} to isolate the phase φ_p induced by the SPR. The reference optical signal I_{REF} provides the frequency reference $I_{RDET}(t)$ at the beat frequency $\gamma\tau$ of the interference signal $I(t)$ as shown in Figure 4A. In an alternative embodiment to that shown in Figure 4A, the reference optical signal I_{REF} is
 15 tapped from the optical signal I_1 and passed directly to the polarizer 32 and the detector 34, without reflection off of a reference target T_{REF} .

The wavelength λ of the lightwave p of the optical signal I_1 is recorded in a memory or other storage device (not shown) as the phase φ_p is measured to establish a relationship between optical wavelength λ and phase φ_p in the vicinity of the resonant
 20 wavelength λ_R . The wavelength λ of the optical signal I_1 is recorded or determined using optical interferometry, homodyne or heterodyne spectral analysis as described in *Fiber Optic Test and Measurement*, edited by Dennis Derickson, ISBN 0-13-534330-5, pages

42-44, or using any other suitable wavelength discrimination technique. Alternatively, the wavelength λ is determined based on a start wavelength λ_1 and start time t_1 , stop wavelength λ_2 and stop time t_2 , and the tuning rate γ at which the tunable optical source 22 is tuned or swept between the start wavelength λ_1 , and the stop wavelength λ_2 in the time interval t_2-t_1 . For a tunable optical source 22 having a linear tuning characteristic over the wavelength range $\lambda_1 - \lambda_2$, a direct mapping between time t_x and wavelength λ_x within the wavelength range $\lambda_1 - \lambda_2$ is established. For example, within the tuning or sweep range of the tunable optical source 22, a wavelength λ_x is determined based on corresponding times t_x at which phase φ_p is measured according to the relationship $\lambda_x = \lambda_1 + (t_x-t_1)\gamma$. When the tunable optical source 22 has non-linear tuning characteristics, those characteristics are used to map designated times within the sweeping or tuning of the tunable optical source 22 to wavelengths λ_x within the wavelength range $\lambda_1 - \lambda_2$. By recording the phase φ_p as a function of time as the tunable optical source 22 is tuned or swept and using the established mapping between times t_x and wavelength λ_x of the tunable optical source 22, phase φ_p versus wavelength λ is determined.

From the relationship between wavelength λ and phase φ_p , the quantity $d\varphi_p/d\lambda$ at the resonant wavelength λ_R or sufficiently close to the resonant wavelength λ_R can be readily determined, where the quantity $d\varphi_p/d\lambda$ represents the sensitivity of the phase φ_p to changes in wavelength λ at the resonant wavelength λ_R .

According to an alternative embodiment of the present invention, measurement of phase φ_p is used to approximate the quantity $d\varphi_p/d\lambda$ at the resonant wavelength λ_R . Figure 2 indicates that in the vicinity of the resonant wavelength, there is a wavelength range wherein the phase shift sensitivity to wavelength change, represented by the quantity $d\varphi_p/d\lambda$ is approximately constant. Thus, the quantity $d\varphi_p/d\lambda$ within this wavelength range provides an approximation of the quantity $d\varphi_p/d\lambda$ at the resonant wavelength. The accuracy of this approximation depends on the uniformity of the slope of the phase φ_p versus wavelength λ in the wavelength range within which the SPR phase transition occurs.

From the quantity $d\varphi_p/d\lambda$ at the resonant wavelength λ_R , and a determination of the quantity $d\lambda/dn_s$, which represents the wavelength sensitivity to refractive index at the resonant wavelength λ_R , the quantity $d\varphi_p/dn_s$, representing the sensitivity of phase φ_p to changes in refractive index n_s , is established as $d\varphi_p/dn_s = (d\varphi_p/d\lambda) (d\lambda/dn_s)$. The quantity $d\lambda/dn_s$ is determined in a variety of ways. In one example, the quantity $d\lambda/dn_s$ is determined from computer simulation of the configuration 10 of Figure 1 using MATLAB or other suitable program or environment to solve the Fresnel reflections at the conductive film-dielectric interface to model the sensitivity of the resonant wavelength λ_R to changes in refractive index n_s . In another example, the quantity $d\lambda/dn_s$ is determined empirically wherein targets T having dielectrics 2 with different known refractive indices $n_{s1}, n_{s2} \dots n_{sx}$ are illuminated sequentially or simultaneously by the optical signal I_1 at wavelengths λ in the vicinity of the resonant wavelength λ_R to determine the resonant wavelength λ_{R1} ,

$\lambda_{R2} \dots \lambda_{RX}$ of the SPR corresponding to each of the refractive indices $n_{S1}, n_{S2} \dots n_{SX}$.

Curve-fitting of the resonant wavelengths $\lambda_{R1}, \lambda_{R2} \dots \lambda_{RX}$ to refractive indices $n_{S1}, n_{S2} \dots n_{SX}$, interpolation, or other suitable techniques are used to establish a mapping between refractive index n_S and resonant wavelength λ_R to determine the quantity $d\lambda/dn_S$

5 at the resonant wavelength λ_R .

The quantity $d\lambda/dn_S$ can also be determined by matching appropriate wave vectors at the interface between the conductive film 1 and the dielectric 2. This includes equating the wave vector $k_{SPR} = w/c ((\varepsilon_1 n_S^2)(\varepsilon_1 + n_S^2))^{1/2}$ of the surface plasmon to the wave vector $kx = n_4(2\pi/\lambda)\sin\phi_{SP}$ of the optical signal I_1 , where ε_1 is the dielectric constant of the
 10 conductive film 1, where n_4 is the refractive index of the prism 4, and where ϕ_{SP} is the angle of incidence of the optical signal I_1 . The quantity $d\lambda/dn_S$ can be derived from the equation of the wave vectors k_{SPR}, kx , as equation (2), where the imaginary component of the dielectric constant ε_1 of the conductive film 1 is set to zero.

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$$\frac{d\lambda}{dn_S} = \frac{n_4 \varepsilon_1}{\frac{n_4 n_S^3}{\lambda} \left(\frac{1}{\varepsilon_1} - 1 \right) + \frac{dn_4}{d\lambda} n_S (n_S^2 + \varepsilon_1)} \quad (2)$$

The alternatives presented for determining the quantity $d\lambda/dn_S$ at the resonant wavelength are exemplary. It is appreciated that any suitable scheme is alternatively used to determine or approximate the quantity $d\lambda/dn_S$ at the resonant wavelength λ_R , or at a

wavelength suitably close to the resonant wavelength λ_R , so that the sensitivity of phase φ_p to changes in refractive index n_s can be established as $d\varphi_p/dn_s = (d\varphi_p/d\lambda)(d\lambda/dn_s)$.

According to an alternative embodiment of the present invention, a mapping between phase φ_p and refractive index n_s is established based on measuring phase φ_p for dielectrics 2 having different refractive indices n_s . In this embodiment, phase φ_p is detected and changes in refractive index n_s of the dielectric 2 are determined from the established mapping. In one example, changes dn_s in refractive index n_s are related to shifts $d\varphi_p$ in phase φ_p at the resonant wavelength λ_R by a constant as provided for example, in *Immunosensor based on optical heterodyne phase detection*, Sensors and Actuators B, vol. 76, Xinglong Yu, et al., (2003), p. 200.

According to another embodiment of the present invention, the phase φ_p is detected versus wavelength λ for two or more targets T with different refractive indices, for example, the refractive index n_s and the refractive index $n_s + \Delta n_s$. The detected phases φ_p corresponding to the refractive indices n_s , $n_s + \Delta n_s$, as shown in Figure 6, are offset contours that result from shifts in resonant wavelength from the resonant wavelength λ_R to the resonant wavelength $\lambda_R + \Delta\lambda_R$ due to the difference in refractive indices Δn_s . A mapping between resonant wavelength and refractive indices can then be used to convert the difference in resonant wavelength $\Delta\lambda_R$ to a corresponding difference in refractive index Δn_s .

In alternative embodiments of the present invention the sensitivity of changes in phase φ_p to changes in wavelength λ in the vicinity of the resonant wavelength λ_R is

modified by misaligning, or rotating, the offset polarizations of the lightwaves p, s of the optical signal I_1 relative to the conventional polarizations p, s at the target T as shown in Figure 5A, to result in lightwaves p', s' having misaligned polarizations p', s' as shown in Figure 5B. Increases in this sensitivity, manifest as increases in the quantity $d\varphi_p/d\lambda$, due to misalignment in polarizations provides corresponding increases in sensitivity of phase to changes in refractive index of the dielectric 2. Figure 7 shows the phase φ_p (indicated as $\varphi_p(p',s')$ of the optical signal I_2 when the optical signal I_1 has lightwaves p', s' that are misaligned relative to the lightwaves p,s. The phase of the optical signal I_2 when the optical signal I_1 has lightwaves p, s is indicated as $\varphi_p(p,s)$ in Figure 7.

Misalignment of polarizations is achieved in a variety of alternative ways. For example, the misalignment is caused by creating a half-wavelength plate birefringence (not shown) in the fiber between the polarization beam combiner 28 and the collimator 30, for example in the embodiment shown in Figure 4A. The misalignment is alternatively achieved by collimating the optical signal I_1 immediately after the polarization beam combiner 28, and interposing a slightly misaligned free-space half-wavelength plate in the beam of the collimated optical signal. Alternatively, the misalignment in polarization components can be achieved by a slight misalignment of the polarization beam combiner 28, with the collimator 30 being placed adjacent to the polarization beam combiner 28.

The sensitivity of changes in phase φ_p to changes in wavelength λ in the vicinity of the resonant wavelength λ_R can be increased or maximized empirically for a given misalignment of polarizations of the optical signal I_1 , for example, by rotating the interposed half-wavelength plates when present, or by rotating the polarization beam

combiner 28 while measuring phase φ_p as the optical wavelength λ is swept or tuned in the vicinity of the resonant wavelength λ_R .

The sensitivity of changes in phase φ_p to changes in wavelength λ in the vicinity of the resonant wavelength λ_R can be increased or optimized based on an analytical determination of the polarization misalignment. In an analytical determination, the electric fields E_{SO} , E_{PO} of the optical signal I_2 corresponding to the lightwaves p , s are expressed by the matrix equation (3).

$$\begin{bmatrix} E_{SO} \\ E_{PO} \end{bmatrix} = \begin{bmatrix} r_s & 0 \\ 0 & r_p e^{j\varphi_p} \end{bmatrix} \begin{bmatrix} a & b \\ -b^* & a^* \end{bmatrix} \begin{bmatrix} E_s \\ E_p \end{bmatrix}$$

In the matrix equation (3), the term r_s is a Jones matrix element for the reflection of the lightwave s at the target T ; the term $r_p e^{j\varphi_p}$ is a Jones matrix element for the reflection of the lightwave p at the target T ; the terms a and b are Jones matrix elements for the polarization misalignment where $a = |a|e^{j\delta_a}$ and where $b = |b|e^{j\delta_b}$; and the terms E_s , E_p are the electric field components of the lightwaves p , s respectively of the optical signal I_1 .

The reflected signal I_2 from the target T is passed through the polarizer 32 to provide an interference signal $I'(t)$, as shown in Figure 5B. The interference signal $I'(t) = |\cos\alpha E_{SO} + \sin\alpha E_{PO}|^2$ is intercepted by the detector 34, where the angle α represents the rotational offset between the lightwaves of the optical signal I_2 and the axis X of the polarizer 32. The detector 34 is responsive to the terms in the interference signal $I'(t)$ in the vicinity of the frequency $\gamma\tau$, which is the frequency difference, or beat frequency, between the lightwaves p' , s' of the optical signal I_1 provided by the tunable optical source 22. The detector 34 can be filtered or otherwise tuned for responsiveness within a narrow

bandwidth about the frequency $\gamma\tau$, to improve sensitivity with which the designated terms in the interference signal $I'(t)$ can be measured or detected. The detector 34 provides an electrical signal $I'_{DET}(t)$ that is represented in equation (4).

$$\begin{aligned}
 I'_{DET}(t) = & \cos^2\alpha |a||b|r_s^2 E_{SO}E_{PO} \cos(2\pi\gamma\tau t + \delta_a - \delta_b) + \\
 5 \quad & \cos\alpha \sin\alpha |a|^2 r_s r_p E_{SO}E_{PO} \cos(2\pi\gamma\tau t + 2\delta_a - \varphi_p) - \\
 & \cos\alpha \sin\alpha |b|^2 r_s r_p E_{SO}E_{PO} \cos(2\pi\gamma\tau t - 2\delta_b + \varphi_p) - \\
 & \sin^2\alpha |a||b|r_p^2 E_{SO}E_{PO} \cos(2\pi\gamma\tau t + \delta_a - \delta_b). \quad (4)
 \end{aligned}$$

High phase sensitivity versus wavelength is achieved based on the equation (4) for a misalignment of the polarizations of the optical signal I_1 , wherein $|b|$ is approximately
 10 equal to the reflectivity r_p of the lightwave p from the target T , and wherein the sum of the phase φ_p of the SPR and the phases of the misalignments $\delta_a + \delta_b$ is an odd multiple of π . In a typical example, an increase in sensitivity is achieved for misalignments of less than 5 degrees between the polarizations of the lightwaves p , s and the polarizations of the lightwaves p' , s' .

15 In alternative embodiments of the present invention shown in Figures 8A-8B, the optical phase detector 20 is scaled, enabling simultaneous or sequential detection of SPR-induced phase shifts from a target T that includes an array of SPR transducers, indicated as targets T_1 - T_N . In Figure 8A, an array of targets T_1 - T_N are illuminated by optical signals I_{11} - I_{1N} provided from the optical signal I_1 by an optical splitter 42 and directed via
 20 collimators 30_1 - 30_N . An imaging element 43, such as a lens is interposed between the array of targets T_1 - T_N and a detector 44 that includes an array of detector elements D_1 - D_N . The imaging element 43 is positioned in the optical path between the array of targets T_1 - T_N and the polarizer 32 as shown, or between the polarizer 32 and the detector array 44. The

imaging element 43 provides a map or other correspondence between the physical locations of the targets T_1 - T_N and physical locations of detector elements D_1 - D_N in the detector array 44, so that optical signals I_{21} - I_{2N} reflected from the array of targets T_1 - T_N are intercepted by corresponding detector elements D_1 - D_N in the detector array 44. The
 5 detector elements D_1 - D_N provide detected signals $I_{1DET}(t)$ - $I_{NDET}(t)$ to a phase comparator or other processor 46. The processor 46 compares the detected signals $I_{1DET}(t)$ - $I_{NDET}(t)$ to the frequency reference $I_{RDET}(t)$ to extract corresponding phases of the signals I_{21} - I_{2N} reflected from each of the targets within the array of targets T_1 - T_N .

In the embodiment shown in Figure 8A, the frequency reference $I_{RDET}(t)$ results
 10 from the reference optical signal I_{REF} that is derived from the optical signal I_1 provided by the tunable optical source 22, via tapping of the optical signal I_1 , polarizing the reference optical signal I_{REF} via a polarizer 47 and detection of the resulting interference signal $I_R(t)$ via detector 44R. In an alternative embodiment, the frequency reference $I_{RDET}(t)$ is provided by a designated one of the detected signals $I_{1DET}(t)$ - $I_{NDET}(t)$, for example the
 15 detected signal $I_{XDET}(t)$. The designated detected signal $I_{XDET}(t)$ corresponds to a target T_X within the array of targets T_1 - T_N . When the target T_X does not induce an SPR phase shift at the wavelength of the optical signal I_{1X} incident on the target T_X , phases extracted by the processor 46 are relative to the phase of the reference optical signal I_{REF} . When the target induces an SPR phase shift at the wavelength of the optical signal I_{1X} incident on
 20 the target T_X , phases extracted by the processor 46 are differential. The differential phase corresponds to differential refractive indices between the targets in the array of targets, relative to the refractive index corresponding to the target T_X .

According to the embodiment of the present invention shown in Figure 8B, a focusing element 47, such as a lens forms a beam B1 from the optical signal I_1 that is

suitably wide to illuminate an array of targets T_1-T_N . The array of targets reflects the beam B1 of the optical signal I_1 to form a beam B2. The imaging element 43 positioned in the optical path between the array of targets T_1-T_N and the polarizer 32 provides a correspondence between the physical locations of the targets T_1-T_N and physical locations of detector elements D_1-D_N in the detector array 44, so that portions of the beam B2 reflected from the corresponding targets positioned within the array of targets T_1-T_N are intercepted by corresponding detector elements D_1-D_N in the detector array 44. The detector elements D_1-D_N provide detected signals $I_{IDET}(t)-I_{NDET}(t)$ to the phase comparator or other processor 46 that compares each of the detected signals $I_{IDET}(t)-I_{NDET}(t)$ to the frequency reference $I_{RDET}(t)$ to extract the phase of the optical signals within the beam B2 that are reflected from each of the targets within the array of targets T_1-T_N .

In the embodiment shown in Figure 8B, the frequency reference $I_{RDET}(t)$ results from the reference optical signal I_{REF} that is derived from the optical signal I_1 provided by the tunable optical source 22, via tapping of the optical signal I_1 , polarizing the reference optical signal I_{REF} via a polarizer 47 and detection of the resulting interference signal $I_R(t)$ via detector 44R. In an alternative embodiment, the frequency reference $I_{RDET}(t)$ is provided by a designated one of the detected signals $I_{IDET}(t)-I_{NDET}(t)$, for example the detected signal $I_{XDET}(t)$. The designated detected signal $I_{XDET}(t)$ corresponds to a target T_X within the array of targets T_1-T_N . When the target T_X does not induce an SPR phase shift at the wavelength of the portion of the optical beam B1 incident on the target T_X , phases extracted by the processor 46 are relative to the phase of the reference optical signal I_{REF} . When the target does induce an SPR phase shift at the wavelength of the optical signal I_{IX} incident on the target T_X , phases extracted by the processor 46 are differential. The

differential phase corresponds to differential refractive indices between the targets in the array of targets, relative to the refractive index corresponding to the target T_x .

Figure 9 shows a flow diagram of a phase detection method 50 in accordance with alternative embodiments of the present invention. In step 51 of the method 50, the lightwave p and the lightwave s are tuned over the wavelength range. In step 52, the frequency offset $\gamma\tau$ between the lightwave p and the lightwave s is provided as the wavelength of the optical signal I_1 is tuned, by imposing a relative delay τ between the lightwave p and the lightwave s . Step 54 includes directing the lightwave p and the lightwave s to the target T to provide the lightwave p_r and the lightwave s_r in response to the lightwave p_r and the lightwave s_r . Step 56 includes detecting a polarization component of the lightwave p_r and a polarization component of the lightwave s_r to provide the detected signal at the frequency offset $\gamma\tau$. In step 58, the phase difference, or phase φ_p , induced by the target T , between the polarization components of the lightwaves p , s , is extracted. Extracting the phase φ_p typically includes phase comparing the detected signal to the frequency reference at the frequency offset $\gamma\tau$. In one example, the frequency reference is derived from detecting the reference optical signal that passes through a polarizer, where the reference optical signal is tapped from the lightwaves p , s of the optical signal I_1 .

While an SPR transducer 10, or array of SPR transducers have been used as exemplary target T according to the embodiments of the present invention, the target T is alternatively any device, element, or system suitable for providing an optical signal I_2 in response to an applied optical signal I_1 , where the optical signal I_2 results from reflection, transmission or other processing of the optical signal I_1 .

response to an applied optical signal I_1 , where the optical signal I_2 results from reflection, transmission or other processing of the optical signal I_1 .

While the embodiments of the present invention have been illustrated in detail, it should be apparent that modifications and adaptations to these embodiments may occur to one skilled in the art without departing from the scope of the present invention as set forth in the following claims.